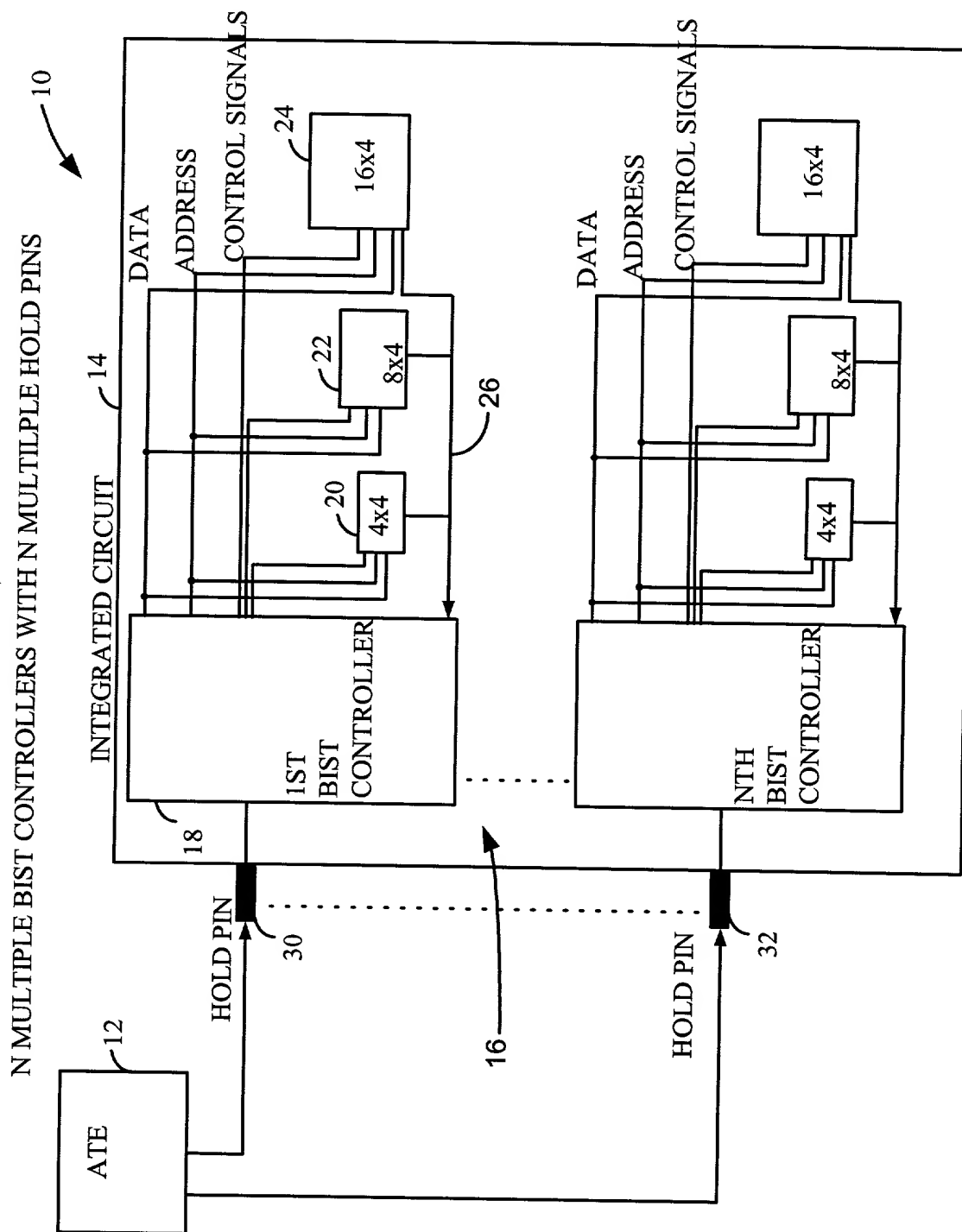
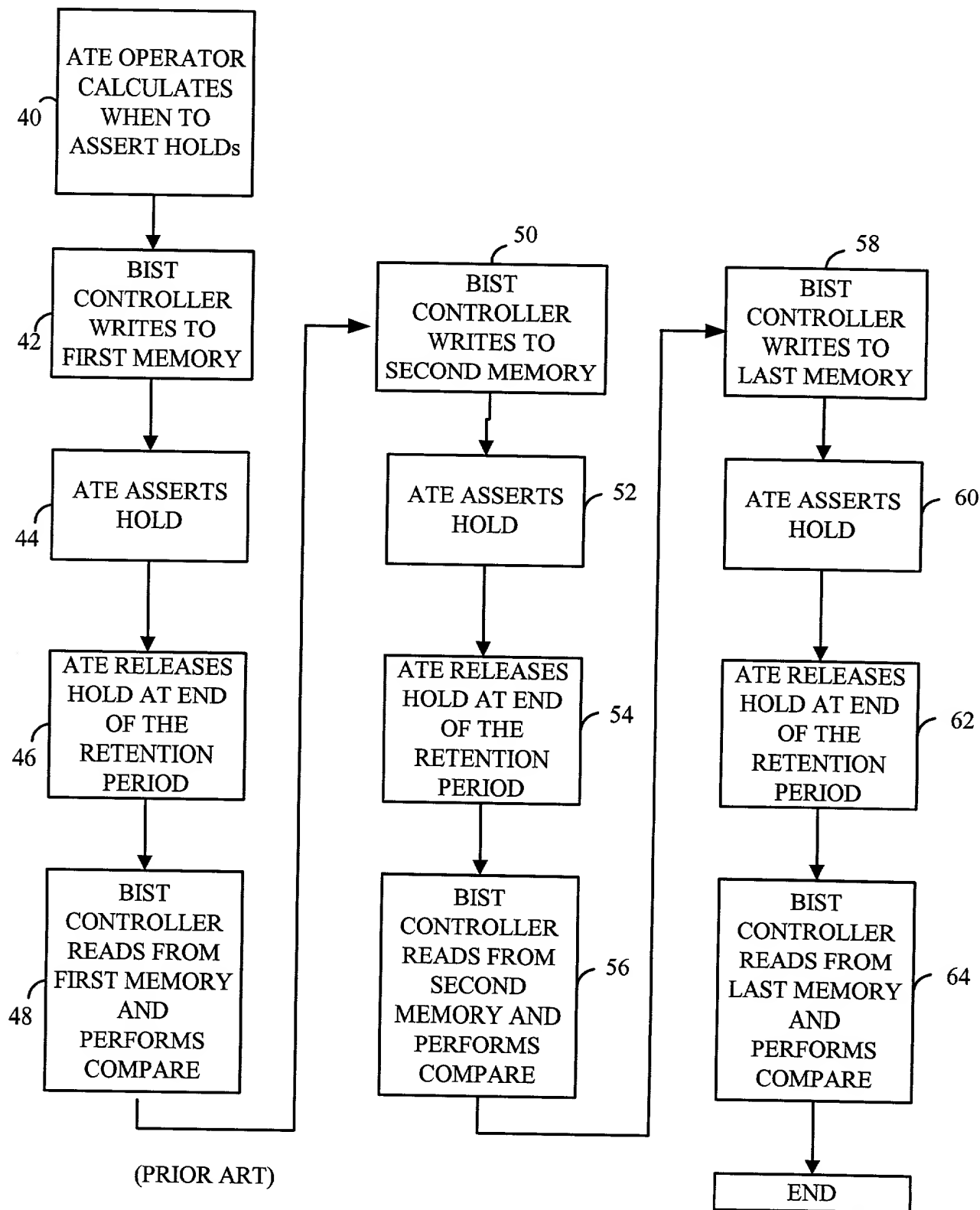


**FIG. 1**  
(PRIOR ART)

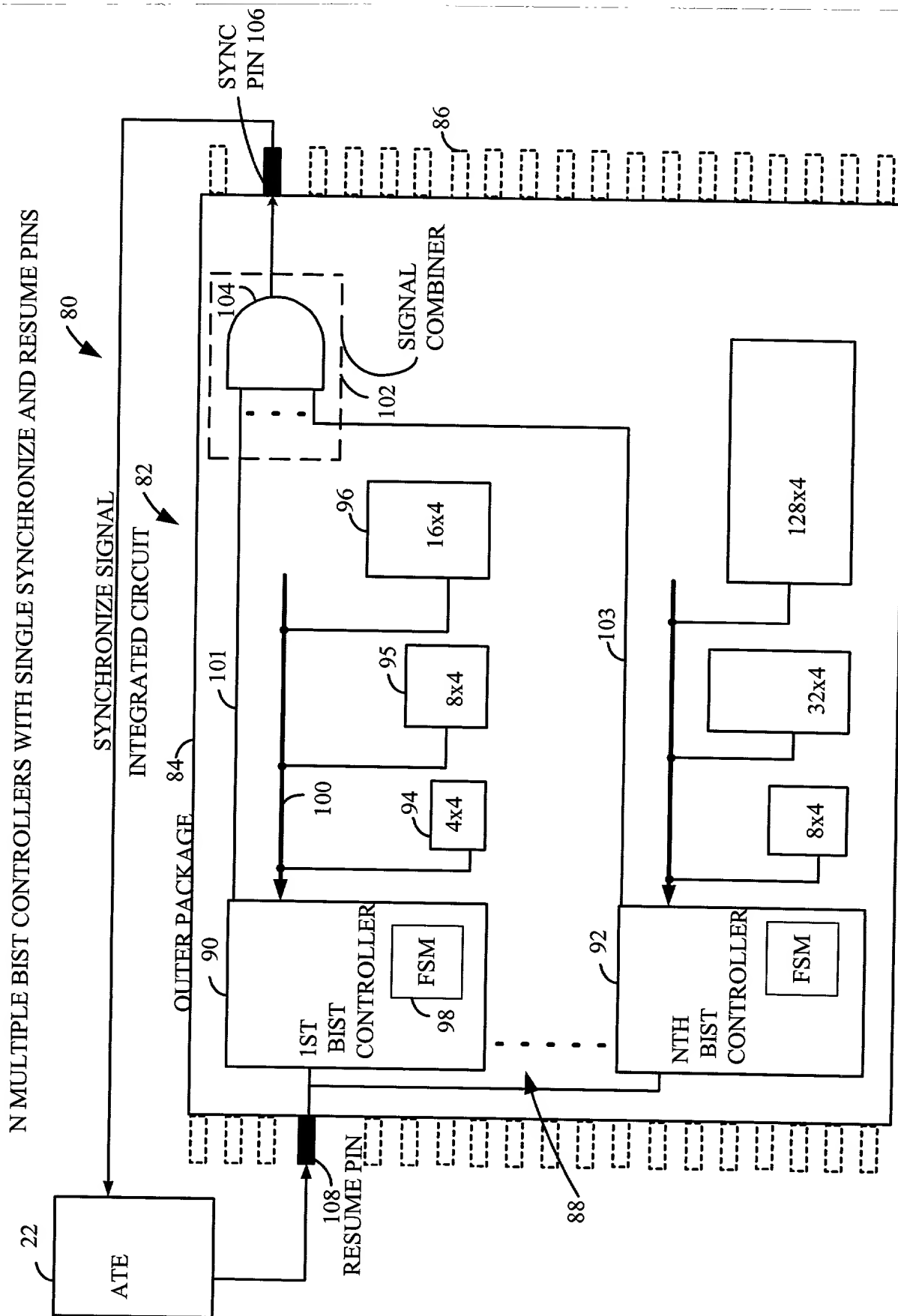


## FIG. 2

TEST ON THREE MEMORIES COUPLED TO A SINGLE SEQUENTIAL BIST  
CONTROLLER USING THREE SEPARATE IDLE PERIODS

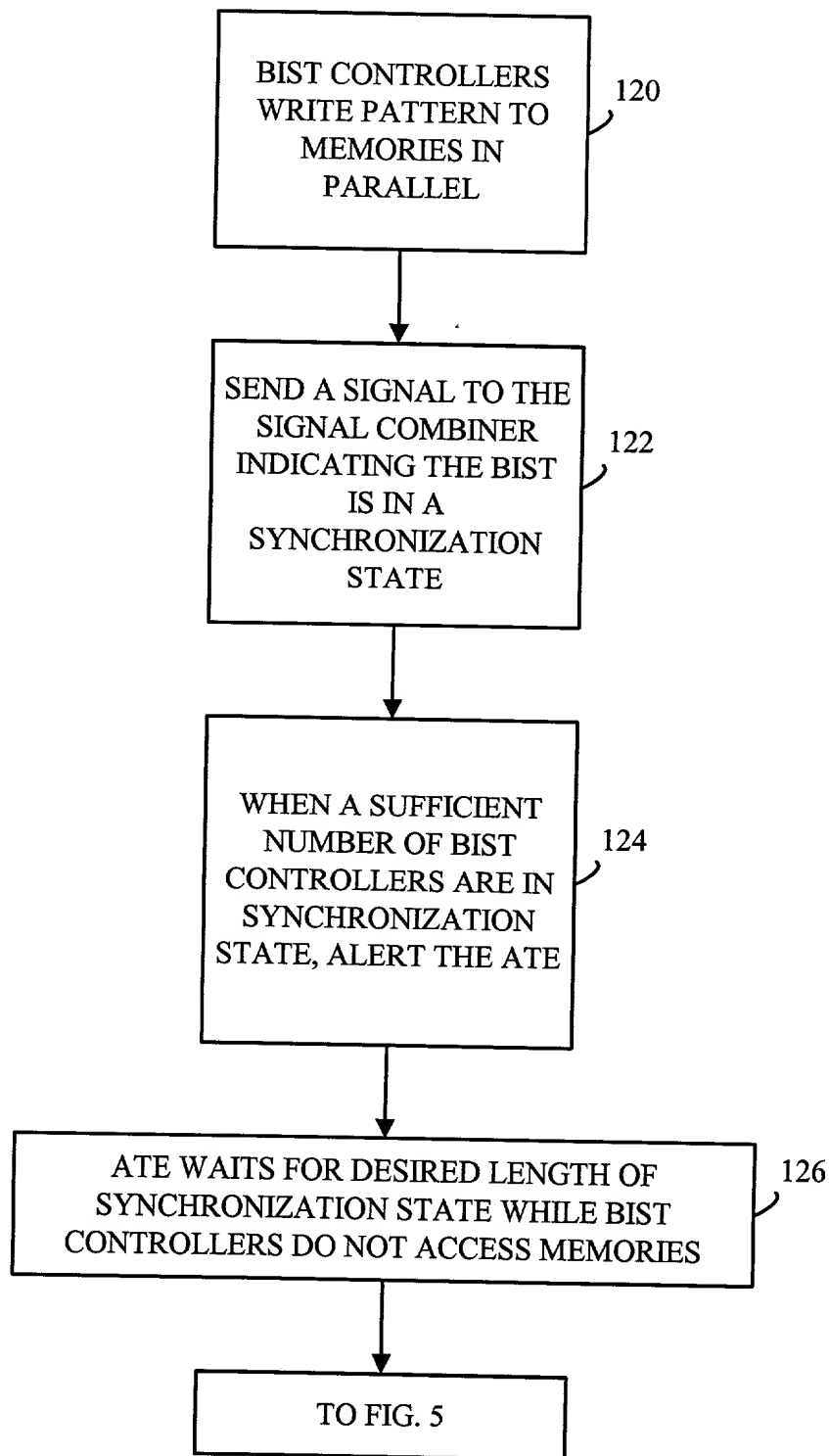


**FIG. 3**



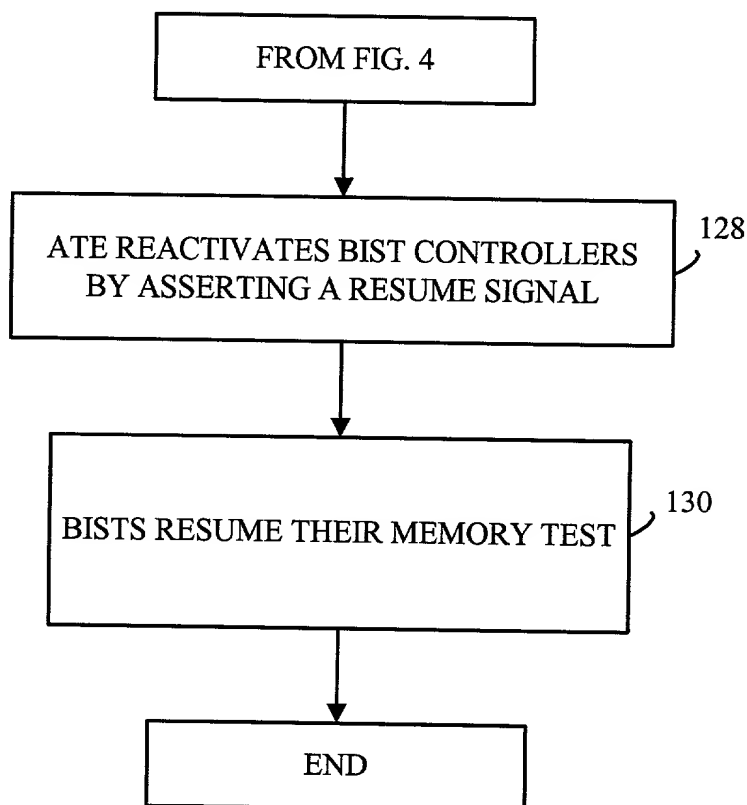
## FIG. 4

### TEST OF MEMORIES WITH MULTIPLE PARALLEL BIST CONTROLLERS USING SYNCHRONIZATION STATE



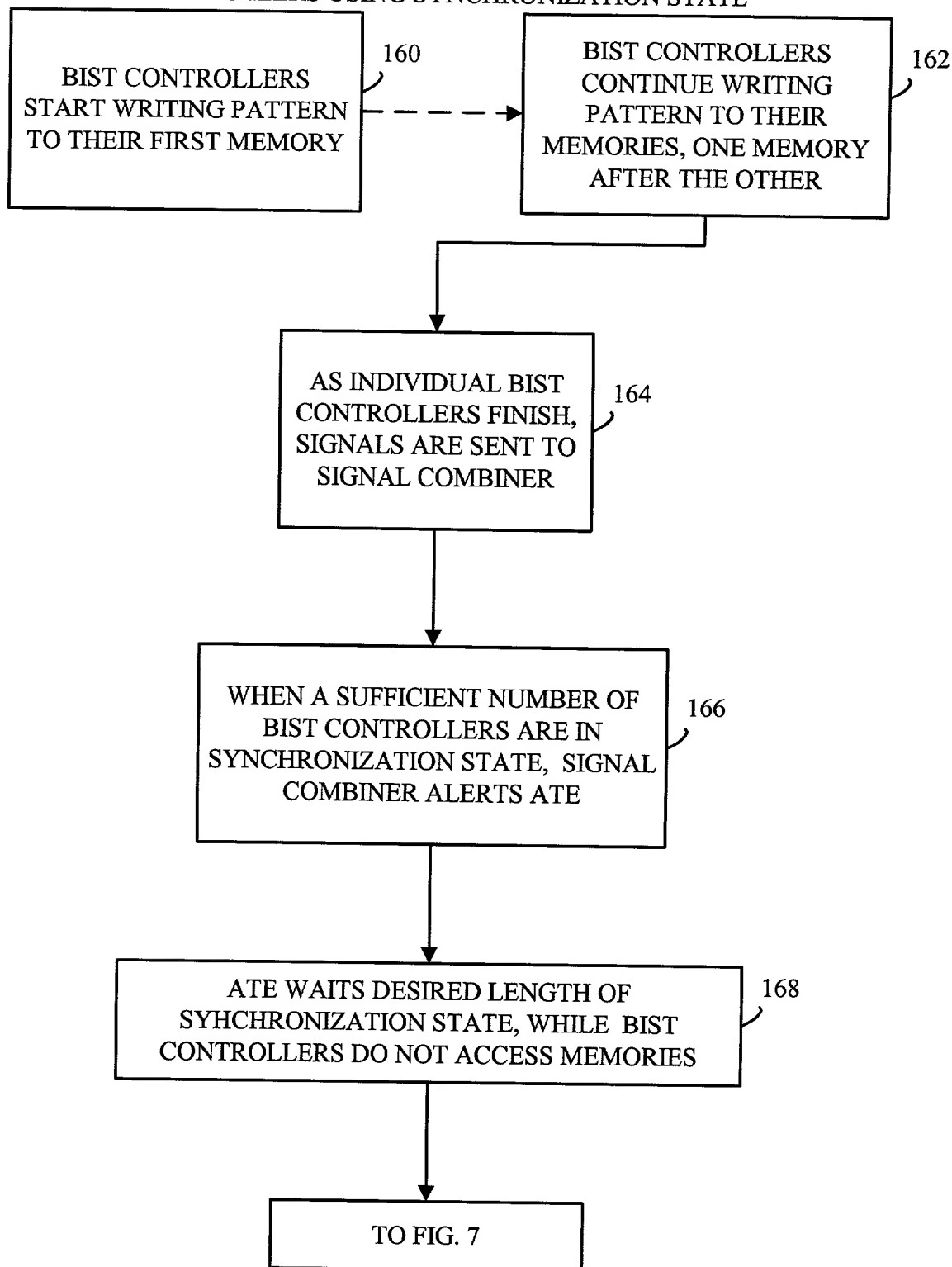
## FIG. 5

### TEST OF MEMORIES WITH MULTIPLE PARALLEL BIST CONTROLLERS USING SYNCHRONIZATION STATE (CONTINUED)



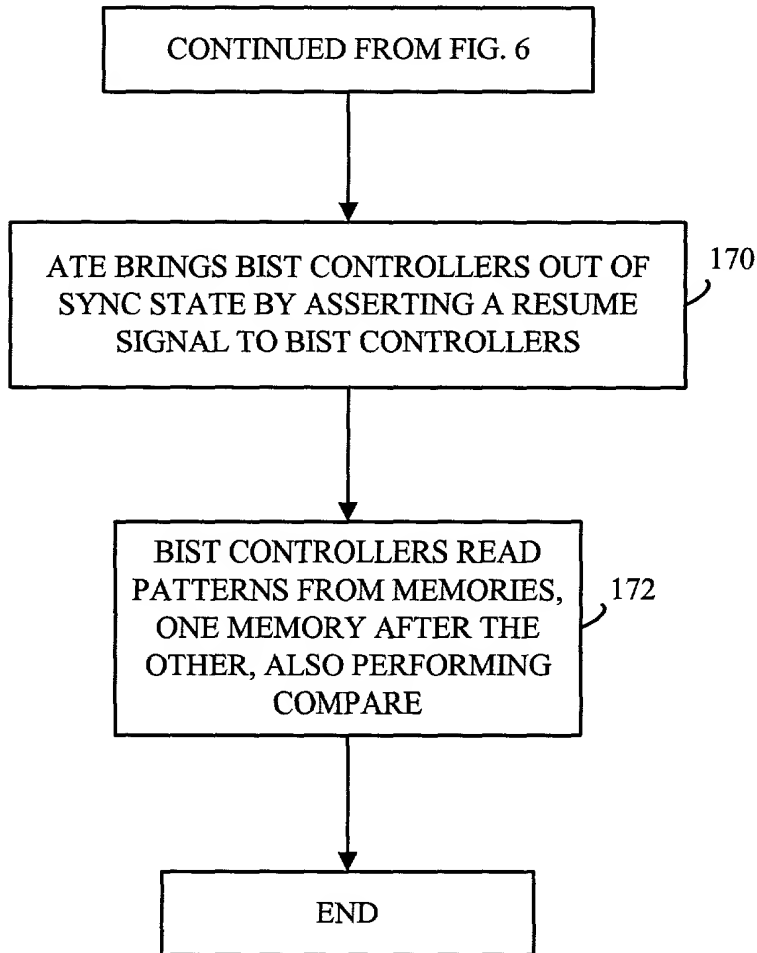
## FIG. 6

### TEST OF MEMORIES WITH MULTIPLE SEQUENTIAL BIST CONTROLLERS USING SYNCHRONIZATION STATE

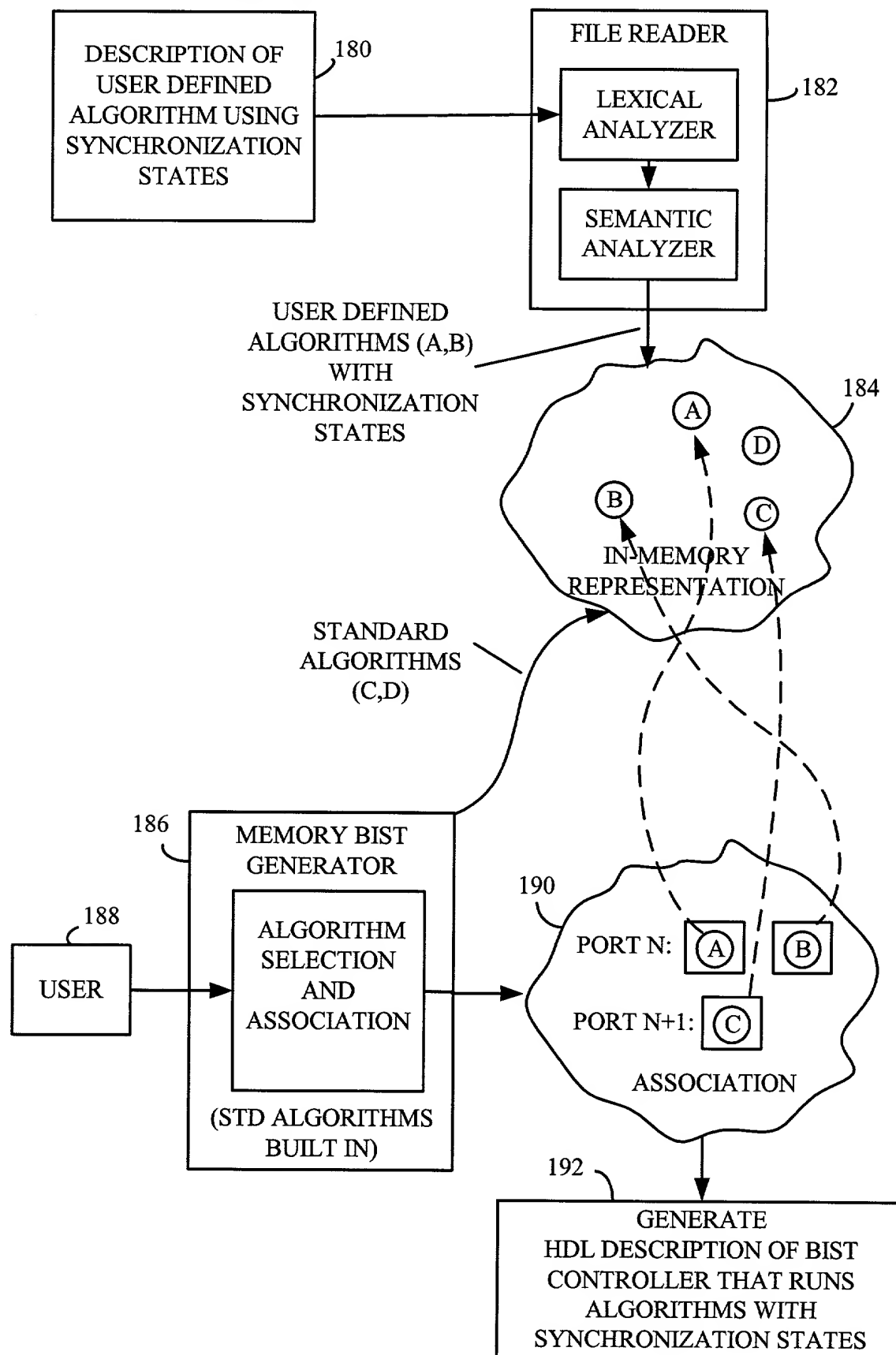


## FIG. 7

### TEST OF MEMORIES WITH MULTIPLE SEQUENTIAL BIST CONTROLLERS USING SYNCHRONIZATION STATE (CONTINUED)



**FIG. 8** — BIST CONTROLLER GENERATOR





## FIG. 9

GENERATING A BIST CONTROLLER THAT RUNS USER  
DEFINABLE ALGORITHMS WITH SYNC KEYWORD

